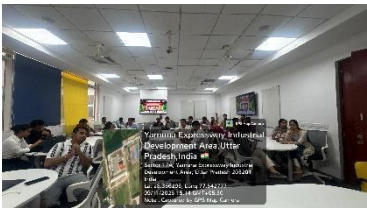


Event Report 2025 - 26

Title of Activity*	Expert Talk” <i>Digital Forensic & Image security</i> ”
Organized by (School/Centre Name)*	School of Computer Application & Technology
Program Theme*	Expert Talk
Date*	11 th Sept, 2025
Time*	3:00 pm to 4:30 pm
Poster*	
Venue* (Block and Room No.)	C-132
SDG Attained* (Mention SDG number/s)	3,4,9
YouTube/Facebook Link: (if live steamed or video posted on FB/YT)	NA
Social media link* (promoting in any one Facebook/Instagram/WhatsApp/Twitter is mandatory)	Instagram, LinkedIn
No. of Students* (only no. to be written, list in excel or word should be maintain at department level as proof for any further requirement)	05
No. of Faculty* (only no. to be written , list in excel or word should be maintain at department level as proof for any further requirement)	40
No. of External Participants (students + faculty) [write NA if not applicable]	NA
(Geotag) Photograph-1*	

(Geotag) Photograph-2	 Yamuna Expressway Industrial Development Area, Uttar Pradesh, India Sector 17A, Uttar Pradesh 203201, India Lat 28.366294, Long 77.542778 09/11/2025 15:44 GMT+05:30
Description (min 250 to max 800 words)*	The SCAT is organizing an Expert Talk on “Counterfeit IC Detection” to shed light on one of the most critical challenges in the semiconductor and electronics industry. Counterfeit Integrated Circuits (ICs) pose a serious threat to technology reliability, product safety, and national security. With the growing demand for electronic components across various sectors—such as defense, healthcare, automotive, and consumer electronics—the risk of counterfeit ICs entering the supply chain has significantly increased. These fake or tampered components can lead to device malfunction, financial losses, and potential hazards in mission-critical applications. This expert session will explore advanced techniques used to detect and prevent counterfeit ICs, including electrical testing, physical inspection, chemical analysis, X-ray imaging, and machine learning-based detection methods. The talk will also cover emerging research in material analysis, traceability, and the use of blockchain technology to secure the semiconductor supply chain. Participants will gain practical insights into identifying counterfeit components, understanding failure mechanisms, and implementing quality assurance strategies to protect against counterfeit infiltration. The session aims to provide students, researchers, and industry professionals with a comprehensive understanding of the threat landscape, detection methodologies, and prevention frameworks for counterfeit ICs. By interacting with the expert, attendees will learn about real-world case studies, technological advancements, and future trends in hardware security. This engaging talk will encourage participants to explore careers and research opportunities in semiconductor forensics, hardware security, and electronic supply chain management, ultimately contributing to safer and more trustworthy electronic systems.
Details of Keynote speaker/ Special Guest <i>(Name, Institute/ Company name, Designation, contact no.)</i>	Dr . Rajat Subhra Chakrabort Professor & Associate DEAN CSE, IIT Kharagpur
Student Coordinators	Arhaan Jawed Ayush Raturi Shreshth Khanna Niyanshi

Report Submitted by* (*write
faculty coordinator name, contact
number*)

[illegible]

Fields marked with '' are mandatory*